OIPE





Manager (1)

Hsiao, Tommy C.; Hui, Angela T.; Ogle, Robert B.; Pham, Tuan Du

Plat, Marina V.; Ramsbey, Mark T.; Shen, Lewis

Assignee:

Advanced Micro Devices, Inc.

Title:

Polished Flash Process With Metal Gates And Improved Planarity

Serial No.:

09/430,366

Filing Date:

October 28, 1999

Examiner:

J. Chen

Group Art Unit:

2813

Docket No.:

M-7523 US

Newport Beach, California August 6, 2001

BOX RCE

COMMISSIONER FOR PATENTS

Washington, D. C. 20231

RESPONSE TO OFFICE ACTION

Dear Sir:

This is a response to the April 6, 2001 Office Action. Submitted herewith are also the following documents:

- 1. A petition for a one-month extension of time pursuant to 37 CFR 1.136(a).
- 2. A Request for Continued Examination (RCE) pursuant to 37 CFR 1.114.
- 3. A written statement summarizing a telephonic interview with Examiner Jack

Chen held on August 3, 2001, pursuant to 37 CFR 1.133(b).

TECHNOLOGY CENTER 2800

LAW OFFICES OF SKJERVEN MORRILL MACPHERSON LD

25 METRO DRIVE SUITE 700 SAN JOSE, CA 95110 (408) 453-9200 FAX (408) 453-7979